

386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Fax: +82-31-339-9855 Tel: +82-31-339-9970 http://www.certitek.com/



EMC TEST REPORT For FCC

Test Report No. CTK02-F025

Date of Issue March 7, 2002 :

Model/Type No: B15CL

Kind of Product **CRT Monitor**

Applicant Hansol Electronics Inc.

Applicant Address 27-29, Hanchon-Ri, Ducksan-Myun, Jinchon-Gun, Chungbuk,

365-840, Korea

Manufacturer Hansol Electronics Inc.

Manufacturer Address 27-29, Hanchon-Ri, Ducksan-Myun, Jinchon-Gun, Chungbuk,

365-840, Korea

Contact Person Mr. S. P. Yang

Telephone +82-43-530-8503

Received Date February 5, 2002

Test period Start: Feb. 6, 2002 End: Mar. 7, 2002

☑ In Compliance ■ Not in Compliance Test Results

The test results presented in this report relate only to the object tested.

CERTITEK Standards Laboratory Co., Ltd. is accredited by Korea Laboratory Accreditation Scheme (KOLAS) which signed the International Laboratory Accreditation Cooperation (ILAC) Mutual Recognition Arrangement (MRA) for the above test item(s) and test method(s).

Tested by

Michael Jang

EMC Test Engineer

Date: March 7, 2002

Reviewed by

James Hong

EMC Technical Manager

Date: March 7, 2002

Form No.: CTK-FF1.1

Page 1 of 15



386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Fax: +82-31-339-9855 Tel: +82-31-339-9970 http://www.certitek.com/



REPORT REVISION HISTORY

Date	Revision	Page No
Mar. 7, 2002	(CTK02-F025) Issued	All
-		

This report shall not be reproduced except in full, without the written approval of CERTITEK Standards Laboratory Co., Ltd. This document may be altered or revised by CERTiTEK Standards Laboratory Co., Ltd. personnel only, and shall be noted in the revision section of the document. Any alteration of this document not carried out by CERTITEK Standards Laboratory Co., Ltd. will constitute fraud and shall nullify the document.

Test Report No.: CTK02-F025 Date: March 7, 2002

Form No.: CTK-FF1.1





CERTITEK Standards Laboratory Co., Ltd.
386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100
Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/

TABLE OF CONTENTS

1.0 General Product Description	4
1.1 Model Differences	4
1.2 Device Modifications	4
1.3 EUT Configuration(s)	5
1.6 Calibration Details of Equipment Used for Measurement	6
1.7 Test Facility	6
1.8 Measurement Procedure	
1.9 Laboratory Accreditations and Listings	7
2.0 Emissions Test Regulations	8
2.1 Conducted Voltage Emissions	9
2.2 Radiated Electric Field Emissions	10
Configurations	11
APPENDIX A - TEST DATA	12
Conducted Voltage Emissions (Quasi-Peak reading)	12
Radiated Electric Field Emissions (Quasi-Peak reading)	



Fax: +82-31-339-9855 Tel: +82-31-339-9970 http://www.certitek.com/



General Product Description 1.0

THE PIC	duct is a	a CIXI IV	ioriitor.		
1.0.1	Tested ⊠	Unless Model Tests	otherwise indicated, B15CL.		were considered to be
1.0.2	Equip	ment \$	Size, Mobility and	Identifica	ation
	Mobility	sions: y: No.:	371 by 398 by 375 ☐ Hand-Held ☒ 1	Гable-top	⊠ mm □ in □ Floor-standing
1.0.3	Electr	ical Ra	atings		
			AC100-240V, 1.3A Not applicable		
1.0.4	Test \	/oltage	e & Frequency		
			ed otherwise on the in equency was as indica		ata sheet or test results, the tes
	Voltage Freque	ency:	120VAC 60Hz		
1.0.5	Clock	& Oth	er Frequencies Ut	ilized	
	 Pre- Vide OSI Syr 	-Amp : eo outp D (On S nc Proce	C: 150kHz 110MHz ut: 75MHz creen Display) IC: 96 essor: 15-150kHz (Ho 50-180Hz (Au ntroller: 8-12MHz	rizontal), 3	35-200Hz (Vertical),

1.1 **Model Differences**

Not applicable

1.2 **Device Modifications**

The following modifications were necessary for compliance:

Addition to the capacitor - C433 (0.01uF/2kV)

Test Report No.: CTK02-F025 Page 4 of 15

Date: March 7, 2002



386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



EUT Configuration(s) 1.3

See Appendix A for individual test set-up configuration(s). The following peripheral devices and/or interface cables were connected during the measurement:

Peripheral Devices

Device	Manufacturer	Model No.	Serial No.	FCC ID or DoC
PC	Hewlett Packard	DTPC-17	SG01501776	DOC
MOUSE (Serial type)	Microsoft	BASM1	4475951-20000	DOC
MOUSE (PS/2 type)	PANWEST	Cyber Beetle	PM1F184045737	DOC
MOUSE (USB type)	PANWEST	Cyber Beetle	PM1F154000055	DOC
MOUSE (USB type)	PANWEST	Cyber Beetle	PM1F144009945	DOC
KEYBOARD	World Com Mart	KB120	-	D840902 MIC
Game Pad	Microsoft	Sidewinder game pad	03426853	C3KMGP1
HEADSET	CAMAC	CMK-C3	-	-
PRINTER	Seiko Epson	Stylus Color 460	BWCE136524	DOC

□ Cable Description

#	Description	Ferrited	Length (m)	Other Details
1	AC Power, Unshielded	No	1.8	Connect to AC Power from EUT
2	AC Power, Unshielded	No	1.8	Connect to AC Power from PC
3	AC Power, Unshielded	No	1.8	Connect to AC Power from printer
4	Monitor cable, Shielded	Yes	1.8	Connect to PC
5	Printer cable, Shielded	Yes	1.8	Connect to PC
6	Mouse cable, Shielded	No	2.0	USB Type
7	Mouse cable, Shielded	No	2.0	USB Type
8	Mouse cable, Shielded	No	2.0	PS/2 Type
9	Mouse cable, Shielded	No	2.0	Serial Type
10	Keyboard cable, Shielded	No	2.0	-
11	Line in cable, Unshielded	No	1.5	-
12	Headset cable, Unshielded	No	2.0	-
13	Game Pad cable, Unshielded	No	2.0	-

n/a = not available

1.4 **Test Software**

☐ Pinging Name / Manufacturer / Version / Type of Pattern - EMC Test / Compaq Computer / 1.0 / Scrolling 'H'

1.5 **EUT Operating Mode(s)**

Equipment under test was operated during the measurement under the following conditions: ☐ Test program (H-Pattern) ☐ Test program (color bar) ☐ Standby ☐ Test program (customer specific)

☐ Practice operation Resolution / Refresh Rate - 800 x 600 / optimum and 1280 x 1024 / 60Hz

Page 5 of 15 Test Report No.: CTK02-F025

Date: March 7, 2002



386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



1.6 Calibration Details of Equipment Used for Measurement

Test equipment and test accessories are calibrated on regular basis. The maximum time between calibrations is one year or what is recommended by the manufacturer, whichever is less. All test equipment calibrations are traceable to the Korea Research Institute of Standards and Science (KRISS), therefore, all test data recorded in this report is traceable to KRISS.

1.7 Test Facility

The measurement facility is located at 386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100. The sites are constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22.

1.8 Measurement Procedure

Preliminary AC power line conducted emissions tests were performed shielded room. To find worst mode, several typical mode and typical cable position were tested. Final AC power line conducted emissions test was performed shielded room. (location is same as Preliminary test)

Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

Preliminary radiated emissions test were performed anechoic chamber (Distance of antenna and EUT was 3 m). To find worst mode, several typical mode and typical cable position were tested and peak level and frequency were recorded.

Final radiated emissions test was performed Open Area Test Site. Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

* Measurement procedures was In accordance with ANSI C63.4-1992 7.2.3, 7.2.4, 8.3.1.1, 8.3.1.2

Test Report No.: CTK02-F025 Page 6 of 15

Date: March 7, 2002



6-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



1.9 Laboratory Accreditations and Listings

Country	Agency	Scope of Accreditation	Logo
USA	FCC	3 and 10 meter Open Area Test Sites to perform FCC Part 15/18 measurements.	FC 93250
JAPAN	VCCI	10 meter Open Area Test Site and one conducted site.	R-948, C-986
KOREA	MIC	EMI (CE, RE) EMS (ESD, Burst, RS, Surge, CS, Power-Frequency Susceptibility, Voltage Dips and Short Interruptions)	No. 51, KR0025
International	KOLAS	EMC	KOLAS NO.118

Test Report No.: CTK02-F025 Date: March 7, 2002

e: March 7, 2002
This Report shall not be reproduced except in full without the written approval of CERTITEK

Form No.: CTK-FF1.1

Page 7 of 15



CERTITEK Standards Laboratory Co., Ltd. 386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



2.0 **Emissions Test Regulations**

The emissions tests were performed according	to following regulations:	
☐ EN 50081-1 /1992		
☐ EN 55011 /1998	☐ Group 1 ☐ Class A	☐ Group 2 ☐ Class B
☐ EN 55013 /A12:1994		
□ EN 55014 /1987	☐ Household appliance☐ ☐ Portable tools☐ ☐ Semiconductor dev	
☐ EN 55014 /A2:1990		
□ EN 55014 /1993	☐ Household appliance☐ Portable tools☐ Semiconductor dev	
☐ EN 55015 /1987 ☐ EN 55015 /A1:1990 ☐ EN 55015 /1993		
☐ EN 55022 /A1:1995	☐ Class A	☐ Class B
☐ EN 55022 /1998	☐ Class A	☐ Class B
☐ EN 61000-3-2 Ed.2:2001; IEC 61000-3-2 Ed. ☐ EN 61000-3-3 /1995 (EN 60555 Part 3 /4.87		
□ BS		
☐ VCCI V-3/99.05 : 1999	☐ Class A	☐ Class B
☐ FCC Part 15 SUBPART B	☐ Class A	☐ Class B
☐ AS 3548 (1992)	☐ Class A	☐ Class B
☐ CISPR 11 (1990)	☐ Group 1 ☐ Class A	☐ Group 2 ☐ Class B
☐ CISPR 22 (1993)	☐ Class A	⊠ Class B

Test Report No.: CTK02-F025

Date: March 7, 2002 This Report shall not be reproduced except in full without the written approval of CERTITEK



386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



2.1 Conducted Voltage Emissions

Test Date March 7, 2002 **Test Location** EMI-CE: Shielded Room Test Instruments Rohde Schwarz ESHS30 828144/002 **Test Accessories** \square LISN **EMCO** 3825/2 9206-1971 □ LISN **EMCO** 3825/2 9409-2246 3825/2 9607-2574 **EMCO** ☑ Control PC HP Vectra 500 SG72000192 **Frequency Range of Measurement** ☐ 450 kHz to 30 MHz Instrument Settings IF Band Width: 9 kHz **Test Results** The requirements are: minimum margin is 3.6 dBµV at 0.15 MHz NOT MET limit exceeded by maximum of ____ dBµV at ____ MHz

Remarks

☐ NOT APPLICABLE

See Appendix A for test data.

Test Report No.: CTK02-F025 Page 9 of 15
Date: March 7, 2002



Remarks

See Appendix A for test data

CERTITEK Standards Laboratory Co., Ltd.

386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



2.2 **Radiated Electric Field Emissions**

Test Date March 7, 2002 **Test Location** ☑ EMI-OATS: Testing was performed at a test distance of 10 m. ☐ EMI-OATS: Testing was performed at a test distance of 3 m **Test Instruments** Rohde Schwarz ESVS30 826638/008 **Test Accessories** □ ULTRA Broadband Antenna R & S HL562 361324/014 ☐ Biconical Antenna Schwarzbeck BBA9106 41-00201 ☐ Biconical Antenna **EMCO** 3110B 9607-2564 ☐ Log-periodic Antenna **EMCO** 3146 9607-4567 Frequency Range of Measurement 30 MHz to 2 GHz Instrument Settings IF Band Width: 120 kHz **Test Results** The requirements are: minimum margin is 3.00 dB (μ V/m) at 161.0 MHz □ NOT MET limit exceeded by maximum of ____ dB(μV/m) at ____ MHz ☐ NOT APPLICABLE

Test Report No.: CTK02-F025 Page 10 of 15 Date: March 7, 2002

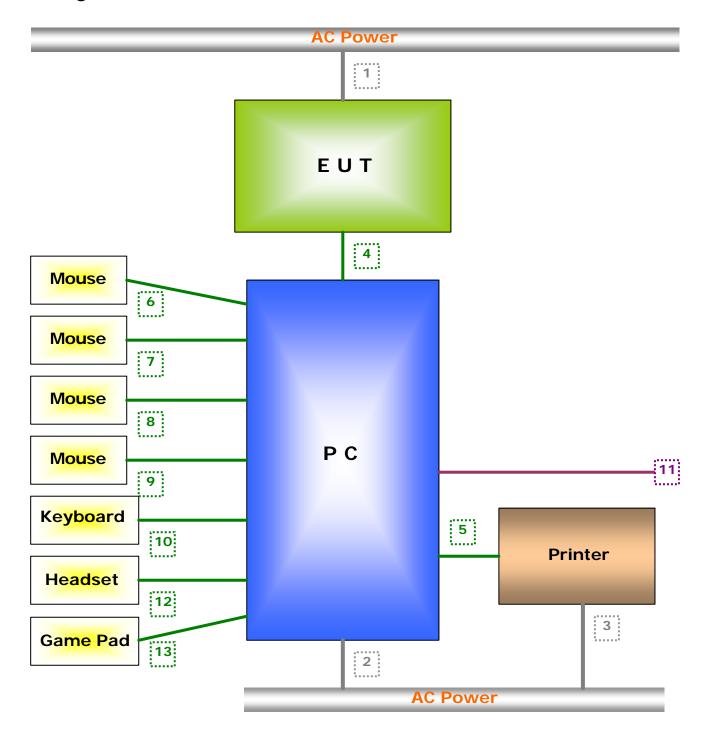
Form No.: CTK-FF1.1



CERTITEK Standards Laboratory Co., Ltd.
386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100
Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



Configuration



Test Report No.: CTK02-F025

Date: March 7, 2002



Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



APPENDIX A - TEST DATA

Conducted Voltage Emissions (Quasi-Peak reading)

800 x 600 / optimum

Frequency	Correction				Quasi	-peak			Ave	rage	
	Fac	tor	Line	Limit	Reading	Result	Margin	Limit	Reading	Result	Margin
[MHz]	LISN	Cable		[dBuV]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dB]
0.15	3.0	0.1	N	66.0	59.3	62.4	3.6	56.0	46.9	50.0	6.0
0.20	2.3	0.1	N	63.8	52.2	54.6	9.2	53.8	40.3	42.7	11.1
0.25	1.5	0.1	N	61.9	46.4	48.0	14.0	51.9	35.5	37.1	14.8
13.08	0.4	0.2	N	60.0	44.8	45.4	14.6	50.0	38.2	38.8	11.3
16.00	0.4	0.2	L	60.0	51.0	51.6	8.4	50.0	36.0	36.6	13.4
20.80	0.6	0.4	L	60.0	46.7	47.7	12.3	50.0	16.8	17.8	32.2
22.40	0.6	0.3	L	60.0	41.9	42.8	17.2	50.0	18.8	19.7	30.3

1280 x 1024 / 60Hz

Frequency	Correction				Quasi	-peak			Ave	rage	
	Fac	tor	Line	Limit	Reading	Result	Margin	Limit	Reading	Result	Margin
[MHz]	LISN	Cable		[dBuV]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dB]
0.21	2.3	0.1	L	63.4	47.8	50.2	13.2	53.4	38.2	40.6	12.8
18.89	0.6	0.2	L	60.0	44.4	45.2	14.9	50.0	39.1	39.9	10.1
22.94	0.6	0.4	L					50.0	34.5	35.5	14.5
23.15	0.6	0.4	L	60.0	41.6	42.6	17.4	50.0	34.8	35.8	14.3
23.22	0.6	0.4	N	60.0	41.4	42.4	17.7	50.0	34.6	35.6	14.4

Test Report No.: CTK02-F025

Date: March 7, 2002

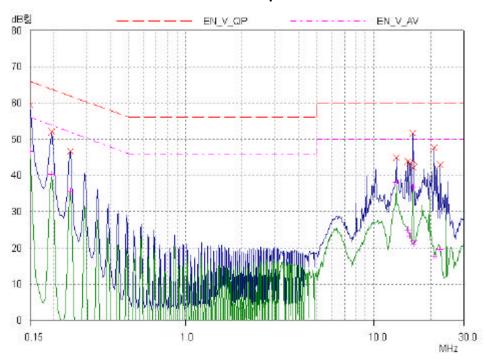
Page 12 of 15

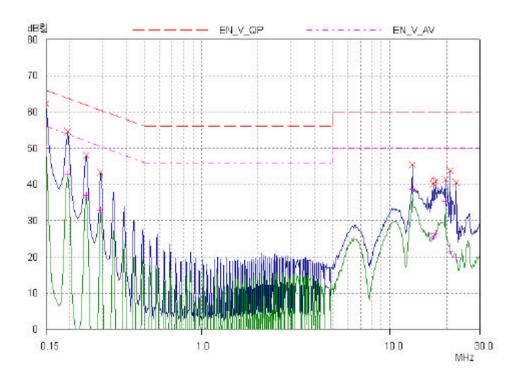


6-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100 Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



800 x 600 / optimum



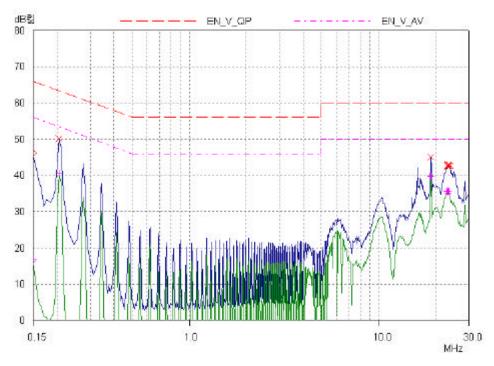


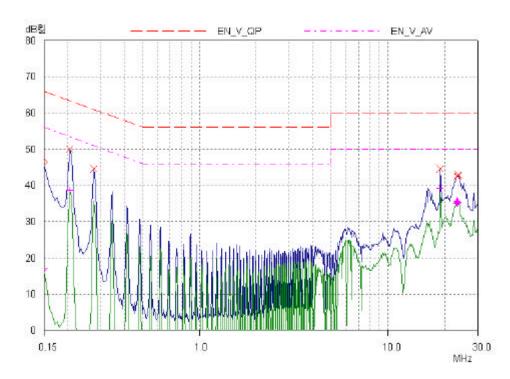


Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



1280 x 1024 / 60Hz





Test Report No.: CTK02-F025

Date: March 7, 2002 This Report shall not be reproduced except in full without the written approval of CERTITEK

Page 14 of 15

Form No.: CTK-FF1.1



Tel: +82-31-339-9970 Fax: +82-31-339-9855 http://www.certitek.com/



Radiated Electric Field Emissions (Quasi-Peak reading)

800 x 600 / optimum

Frequency	Reading	Pol.	Height		Correction Factor		Result	Margin
[MHz]	[dBuV/m]		[m]	Antenna	Cable	[dBuV/m]	[dBuV/m]	[dB]
136.00	16.2	Н	4.0	8.40	2.30	30.0	26.90	3.10
140.00	14.8	V	1.1	8.00	2.40	30.0	25.18	4.82
156.90	11.8	V	1.0	7.40	2.50	30.0	21.74	8.26
252.10	13.7	Н	3.8	9.50	3.10	37.0	26.33	10.67
291.90	14.9	Н	3.8	10.75	3.60	37.0	29.24	7.76
297.30	12.9	Н	4.0	10.90	3.60	37.0	27.41	9.59
762.00	6.3	V	1.2	19.00	6.10	37.0	31.40	5.60
799.00	6.8	Н	3.8	19.50	6.60	37.0	32.91	4.09
808.00	7.1	V	1.0	19.60	6.60	37.0	33.27	3.73
1110.00	0.7	V	1.0	22.70	7.40	37.0	30.80	6.20

1280 x 1024 / 60Hz

Frequency	Reading	Pol.	Height	Correction Factor		Limits	Result	Margin
[MHz]	[dBuV/m]		[m]	Antenna	Cable	[dBuV/m]	[dBuV/m]	[dB]
142.10	16.6	Н	4.0	7.90	2.40	30.0	26.90	3.10
161.00	17.1	Н	3.8	7.30	2.60	30.0	27.00	3.00
170.40	16.7	Н	4.0	7.10	2.60	30.0	26.43	3.57
255.50	21.1	Н	3.5	9.60	3.30	37.0	33.96	3.04
264.90	19.7	Н	3.5	9.90	3.30	37.0	32.85	4.15
283.80	20.1	Н	4.0	10.50	3.40	37.0	33.99	3.01
398.00	9.9	V	1.0	13.50	4.10	37.0	27.49	9.51
660.50	7.1	V	1.2	18.30	5.50	37.0	30.90	6.10

Test Report No.: CTK02-F025

Date: March 7, 2002

Page 15 of 15